STAT 830 Non-parametric Inference Basics

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Big Points

- When estimating a parameter there is a trade-off between bias and variance.
- Variance has the wrong units. Standard Error has the right units.
- Standard errors are usually inversely proportional to \sqrt{n} .
- There is a critical difference between pointwise and uniform (or simultaneous).

Particular Points about non-parametrics

- Empirical CDF is a random function.
- Many ways to get confidence intervals: lots of trade-offs.
- Many parameters are defined in terms of CDF; statistical functionals.
- If a parameter is T(F) then a plug-in estimate is $T(\hat{F}_n)$.
- And $T(\hat{F}_n)$ can be computed by Monte Carlo; this is the bootstrap.

Mathematical Prerequisites I assume you know

- Basic rules for mean, variance, covariance.
- Bernoulli, Binomial distributions, mean, variance, SD.
- Usual estimator of Binomial probability.

The Empirical Distribution Function – EDFpp 97-99 in AoS

• The empirical distribution function is

$$\hat{F}_n(x) = \frac{1}{n} \sum_{i=1}^n 1(X_i \le x)$$

- This is a cdf and is an estimate of F, the cdf of the Xs.
- People also speak of the empirical distribution:

$$\hat{P}(A) = \frac{1}{n} \sum_{i=1}^{n} 1(X_i \in A)$$

- This is the probability distribution corresponding to \hat{F}_n .
- Now we consider the qualities of \hat{F}_n as an estimate, the standard error of the estimate, the estimated standard error, confidence intervals, simultaneous confidence intervals and so on.

Bias, variance and mean squared error

- Judge estimates in many ways; focus is distribution of error $\hat{\theta} \theta$.
- Distribution computed when θ is *true* value of parameter.
- For our non-parametric iid sampling model we are interested in

$$\hat{F}_n(x) - F(x)$$

when F is the true distribution function of the Xs.

• Simplest summary of size of a variable is root mean squared error:

$$extit{RMSE} = \sqrt{\mathrm{E}_{ heta} \left[(\hat{ heta} - heta)^2
ight]}$$

• Subscript θ on E is important – specifies true value of θ and matches θ in the error!

MSE decomposition & variance-bias trade-off

The MSE of any estimate is

$$\begin{aligned} \mathsf{MSE} &= \mathrm{E}_{\theta} \left[(\hat{\theta} - \theta)^2 \right] \\ &= \mathrm{E}_{\theta} \left[(\hat{\theta} - \mathrm{E}_{\theta} (\hat{\theta}) + \mathrm{E}_{\theta} (\hat{\theta}) - \theta)^2 \right] \\ &= \mathrm{E}_{\theta} \left[\left\{ \hat{\theta} - \mathrm{E}_{\theta} (\hat{\theta}) \right\}^2 \right] + \left\{ \mathrm{E}_{\theta} (\hat{\theta}) - \theta \right\}^2 \end{aligned}$$

- In making this calculation there was a cross product term which is 0.
- ullet The two terms each have names: the first is the variance of $\hat{ heta}$ while the second is the square of the bias.
- **Definition**: The **bias** of an estimator $\hat{\theta}$ is

$$\operatorname{bias}_{\hat{\theta}}(\theta) = \operatorname{E}_{\theta}(\hat{\theta}) - \theta$$

So our decomposition is

$$MSE = Variance + (bias)^2$$
.

Usually find a trade-off: making variance smaller increases bias.

Applied to the EDF

• The EDF is an unbiased estimate of F. That is:

$$E[\hat{F}_n(x)] = \frac{1}{n} \sum_{i=1}^n E[1(X_i \le x)]$$
$$= \frac{1}{n} \sum_{i=1}^n F(x) = F(x)$$

so the bias is 0.

The mean squared error is then

$$MSE = Var(\hat{F}_n(x)) = \frac{1}{n^2} \sum_{i=1}^n Var[1(X_i \le x)] = \frac{1}{n} F(x)[1 - F(x)].$$

- This is very much the most common situation: the MSE is proportional to 1/n in large samples.
- So the RMSE is proportional to $1/\sqrt{n}$.
- RMSE is measured in same units as $\hat{\theta}$ so is scientifically right.

Biased estimates

- Many estimates exactly or approximately averages or ftns of averages.
- So, for example,

$$\overline{X} = \frac{1}{n} \sum_{i=1}^{n} X_i$$
 and $\overline{X^2} = \frac{1}{n} \sum_{i=1}^{n} X_i^2$

are unbiased estimates of E(X) and $E(X^2)$.

• We might combine these to get a natural estimate of σ^2 :

$$\hat{\sigma}^2 = \overline{X^2} - \overline{X}^2$$

• This estimate is biased:

$$\mathrm{E}\left[(\overline{X})^2\right] = \mathrm{Var}(\overline{X}) + \left[\mathrm{E}(\overline{X})\right]^2 = \sigma^2/n + \mu^2.$$

So the bias of $\hat{\sigma}^2$ is

$$\mathrm{E}\left[\overline{X^2}\right] - \mathrm{E}\left[(\overline{X})^2\right] - \sigma^2 = \mu_2' - \mu^2 - \sigma^2/n - \sigma^2 = -\sigma^2/n.$$

Relative sizes of bias and variance

- In this case and many others the bias is proportional to 1/n.
- The variance is proportional to 1/n.
- The squared bias is proportional to $1/n^2$.
- So in large samples the variance is more important!
- The biased estimate $\hat{\sigma}^2$ is traditionally changed to the usual sample variance $s^2 = n\hat{\sigma}^2/(n-1)$ to remove the bias.
- WARNING: the MSE of s^2 is larger than that of $\hat{\sigma}^2$.

Standard Errors and Interval Estimation

- In any case point estimation is a silly exercise.
- Assessment of likely size of error of estimate is essential.
- A confidence interval is one way to provide that assessment.
- The most common kind is approximate:

estimate $\pm 2 \times$ estimated **standard error**

- This is an interval of values L(X) < parameter < U(X) where U and L are random.
- Justification for the two se interval above?
- \bullet Notation $\hat{\phi}$ is the estimate of $\phi.$ $\hat{\sigma}_{\hat{\phi}}$ is the estimated standard error.
- Use central limit theorem, delta method, Slutsky's theorem to prove

$$\lim_{n\to\infty} P_F\left(\frac{\hat{\phi}-\phi}{\hat{\sigma}_{\hat{\phi}}} \le x\right) = \Phi(x)$$

Pointwise limits for F(x)

• Define, as usual z_{α} by $\Phi(z_{\alpha}) = 1 - \alpha$ and approximate

$$P_F\left(-z_{\alpha/2} \leq \frac{\hat{\phi} - \phi}{\hat{\sigma}_{\hat{\phi}}} \leq z_{\alpha/2}\right) \approx 1 - \alpha.$$

- Solve inequalities to get usual interval.
- Now we apply this to $\phi = F(x)$ for one fixed x.
- Our estimate is $\hat{\phi} \equiv \hat{F}_n(x)$.
- The random variable $n\hat{\phi}$ has a Binomial distribution.
- So $Var(\hat{F}_n(x)) = F(x)(1 F(x))/n$. The standard error is

$$\sigma_{\hat{\phi}} \equiv \sigma_{\hat{F}_n(x)} \equiv \text{SE} \equiv \frac{\sqrt{F(x)[1 - F(x)]}}{\sqrt{n}}.$$

According to the central limit theorem

$$\frac{\hat{F}_n(x) - F(x)}{\sigma_{\hat{F}_n(x)}} \stackrel{d}{\to} N(0,1)$$

• See homework to turn this into a confidence interval.

Plug-in estimates

- Now to estimate the standard error.
- It is easier to solve the inequality

$$\left|\frac{\hat{F}_n(x) - F(x)}{\mathrm{SE}}\right| \leq z_{\alpha/2}$$

if the term SE does not contain the unknown quantity F(x).

- This is why we use an estimated standard error.
- In our example we will estimate $\sqrt{F(x)[1-F(x)]/n}$ by replacing F(x) by $\hat{F}_n(x)$:

$$\hat{\sigma}_{F_n(x)} = \sqrt{\frac{\hat{F}_n(x)[1 - \hat{F}_n(x)]}{n}}.$$

- This is an example of a general strategy: plug-in.
- Start with estimator, confidence interval or test whose formula depends on other parameter; plug-in estimate of that other parameter.
- Sometimes the method changes the behaviour of our procedure and sometimes, at least in large samples, it doesn't.

Pointwise versus Simultaneous Confidence Limits

In our example Slutsky's theorem shows

$$\frac{\hat{F}_n(x) - F(x)}{\hat{\sigma}_{F_n(x)}} \stackrel{d}{\to} N(0,1).$$

- So no change in limit law (alternative jargon for distribution).
- We now have two pointwise 95% confidence intervals:

$$\hat{F}_n(x) \pm z_{0.025} \sqrt{\hat{F}_n(x)[1-\hat{F}_n(x)]/n}$$

or

$$\{F(x): \left| \frac{\sqrt{n}(\hat{F}_n(x) - F(x))}{\sqrt{F(x)[1 - F(x)]}} \right| \le z_{0.025}\}$$

- When we use these intervals they depend on x.
- And we usually look at a plot of the results against x.
- If we pick out an x for which the confidence interval is surprising to us we may well be picking one of the x values for which the confidence interval misses its target.

Simultaneous intervals

So we really want

$$P_F(L(X,x) \le F(x) \le U(X,x) \text{ for all } x) \ge 1 - \alpha.$$

- In that case the confidence intervals are called *simultaneous*.
- Two possible methods: one exact, but conservative, one approximate, less conservative.
- Jargon: exact sometimes means the probability is not an approximation.
- The inequality holds for every *F* and *n*.
- Exact also sometimes means = for all F and not just \geq .
- Conservative means ≥ .

Some simultaneous intervals for F

Dvoretsky-Kiefer-Wolfowitz inequality:

$$P_F(\exists x: |\hat{F}_n(x) - F(x)| > \sqrt{\frac{-\log(\alpha/2)}{2n}}) \le \alpha$$

OR

$$P_F(\forall x: |\hat{F}_n(x) - F(x)| \le \sqrt{\frac{-\log(\alpha/2)}{2n}}) \ge 1 - \alpha$$

- Gives exact, conservative simultaneous confidence band.
- Limit theory:

$$P_F(\exists x : |\sqrt{n}|\hat{F}_n(x) - F(x)| > y) \to P(\exists x : |B_0(F(x))| > y)$$

where B_0 is a *Brownian Bridge* (special Gaussian process).

• In homework value of y given to make $\alpha = 0.05$.

Statistical Functionals

- Not all parameters are created equal.
- In the Weibull model density

$$f(x; \alpha, \beta) = \frac{1}{\beta} \left(\frac{x}{\beta} \right)^{\alpha - 1} \exp\{-(x/\beta)^{\alpha}\} 1(x > 0).$$

there are two parameters: shape α and scale β .

• These parameters have no meaning in other densities.

Example Functionals

But every distribution has a median and other quantiles:

$$p^{\operatorname{th}}$$
-quantile = $\inf\{x : F(x) \ge p\}$.

If r is bounded ftn then every distribution has value for parameter

$$\phi \equiv \mathrm{E}_F(r(X)) \equiv \int r(x) dF(x).$$

- Most distributions have a mean, variance and so on.
- A ftn from set of all cdfs to real line is called a statistical functional.
- Example: $E_F(X^2) [E_F(X)]^2$.

Statistical functionals

The statistical functional

$$T(F) = \int r(x)dF(x)$$

is linear.

- The sample variance is not a linear functional.
- Statistical functionals are often estimated using plug-in estimates so e.g.:

$$T(\hat{F}) = T(\hat{F}) = \int r(x)d\hat{F}_n(x) = \frac{1}{n}\sum_{i=1}^n r(X_i).$$

• Notice that sometimes there is a formula of $T(\hat{F})$.

SEs as functionals

This estimate is unbiased and has variance

$$\sigma_{T(\hat{F})}^2 = n^{-1} \left[\int r^2(x) dF(x) - \left\{ \int r(x) dF(x) \right\}^2 \right].$$

• This can in turn be estimated using a plug-in estimate:

$$\hat{\sigma}_{T(\hat{F})}^2 = n^{-1} \left[\int r^2(x) d\hat{F}_n(x) - \left\{ \int r(x) d\hat{F}_n(x) \right\}^2 \right].$$

- When r(x) = x we have $T(F) = \mu_F$ (the mean)
- The standard error is σ/\sqrt{n} .
- Plug-in estimate of SE replaces σ with sample SD (with n not n-1 as the divisor).

Plug-in estimates of functionals; bootstrap standard errors

- Now consider a general functional T(F).
- The plug-in estimate of this is $T(\hat{F}_n)$.
- The plug-in estimate of the standard error of this estimate is

$$\sqrt{\operatorname{Var}_{\hat{F}_n}(T(\hat{F}_n))}.$$

which is hard to read and seems hard to calculate in general.

• The solution is to simulate, particularly to estimate the standard error.

Basic Monte Carlo

- To compute a probability or expected value can simulate.
- **Example**: To compute P(|X| > 2) use software to generate some number, say M, of replicates: X_1^*, \ldots, X_M^* all having same distribution as X.
- Estimate desired probability using sample fraction.
- R code: x=rnorm(1000000) ; y =rep(0,1000000); y[abs(x)
 >2] =1 ; sum(y)
- Produced 45348 when I tried it. Gives $\hat{p} = 0.045348$.
- Correct answer is 0.04550026.
- Using a million samples gave 2 correct digits, error of 2 in third digit.
- Using M = 10000 is more common. I got $\hat{p} = 0.0484$.
- Estimated SE of \hat{p} is $\sqrt{p(1-p)}/100 = 0.0021$. So error of up to 4 in second significant digit is likely.

The bootstrap

- In bootstrapping X is replaced by the whole data set.
- Generate new data sets (X^*) from distribution F of X.
- Don't know F so use \hat{F}_n .
- **Example**: Interested in distribution of *t* pivot:

$$t=\frac{\sqrt{n}(\bar{X}-\mu)}{s}.$$

- Have data X_1, \ldots, X_n . Don't know μ or cdf of Xs.
- Replace these by quantities computed from \hat{F}_n .
- Call $\mu^* = \int x d\hat{F}_n(x) = \bar{X}$.
- Draw $X_{1,1}^*, \dots, X_{1,n}^*$ an iid sample from the cdf \hat{F} .
- Repeat *M* times computing *t* from * values each time.

Bootstrapping the t pivot

• Here is R code:

```
x=runif(5)
mustar = mean(x)
tv=rep(0,M)
tstarv=rep(0,M)
for( i in 1:M){
    xn=runif(5)
    tv[i]=sqrt(5)*mean(xn-0.5)/sqrt(var(xn))
    xstar=sample(x,5,replace=TRUE)
    tstarv[i]=sqrt(5)*mean(xstar-mustar)/sqrt(var(xstar))
}
```

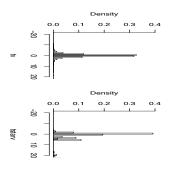
Bootstrapping a pivot continued

- Loop does two simulations.
- in xn and tv we do parametric bootstrapping: simulate t-pivot from parametric model.
- xstar is bootstrap sample from population x.
- tstarv is t-pivot computed from xstar.
- Original data set is

$$(0.7432447, 0.8355277, 0.8502119, 0.3499080, 0.8229354)$$

- So mustar =0.7203655
- Side by side histograms of tv and tstarv on next slide.

Bootstrap distribution histograms



Using the bootstrap distribution

- Confidence intervals: based on *t*-statistic: $T = \sqrt{n}(\bar{X} \mu)/s$.
- Use the bootstrap distribution to estimate P(|T| > t).
- Adjust t to make this 0.05. Call result c.
- Solve |T| < c to get interval

$$\bar{X} \pm cs/\sqrt{n}$$
.

- Get c = 22.04, $\bar{x} = 0.720$, s = 0.211; interval is -1.36 to 2.802.
- Pretty lousy interval. Is this because it is a bad idea?
- Repeat but simulate $\bar{X}^* \mu^*$.
- Learn

$$P(\bar{X}^* - \mu^* < -0.192) = 0.025 = P(\bar{X}^* - \mu^* > 0.119)$$

Solve inequalities to get (much better) interval

$$0.720 - 0.119 < \mu < 0.720 + 0.192$$

Of course the interval missed the true value!

Monte Carlo Study

- So how well do these methods work?
- Theoretical analysis: let C_n be resulting interval.
- Assume number of bootstrap reps is so large that we can ignore simulation error.
- Compute

$$\lim_{n\to\infty} P_F(\mu(F)\in C_n)$$

- Method is asymptotically valid (or calibrated or accurate) if this limit is 1α .
- Simulation analysis: generate many data sets of size 5 from Uniform.
- Then bootstrap each data set, compute C_n .
- Count up number of simulated uniform data sets with $0.5 \in C_n$ to get coverage probability.
- Repeat with (many) other distributions.

R code

```
tstarint = function(x, M=10000)
n = length(x)
must=mean(x)
se=sqrt(var(x)/n)
xn=matrix(sample(x,n*M,replace=T),nrow=M)
one = rep(1,n)/n
dev= xn%*%one - must
tst=dev/sqrt(diag(var(t(xn)))/n)
c1=quantile(dev, c(0.025, 0.975))
c2=quantile(abs(tst),0.95)
c(must-c1[2], must-c1[1], must-c2*se, must+c2*se)
```

R code

```
lims=matrix(0,1000,4)
count=lims
for(i in 1:1000){
x=runif(5)
lims[i,]=tstarint(x)
count[,1][lims[,1]<0.5]=1
count[.2][lims[.2]>0.5]=1
count[,3][lims[,3]<0.5]=1
count[.4][lims[.4]>0.5]=1
sum(count[,1]*count[,2])
sum(count[,3]*count[,4])
```

Results

- 804 out of 1000 intervals based on $\bar{X} \mu$ cover the true value of 0.5.
- 972 out of 1000 intervals based on t statistics cover true value.
- This is the uniform distribution.
- Try another distribution. For exponential I get 909, 948.
- Try another sample size. For uniform n = 25 I got 921, 941.